Hindawi
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Retraction

Retracted: Light-Induced Tyrosine Radical Formation from Ruthenium-Tyrosine Complex Anchored to SnO_2 Semiconductor

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International Journal of Photoenergy has retracted the article titled "Light-Induced Tyrosine Radical Formation from Ruthenium-Tyrosine Complex Anchored to SnO_2 Semiconductor" [1], as it is essentially identical in content with a previously published paper [2]. In particular, the article contains identical figures (namely Figures 4b, 5a, and 5b) with the above mentioned paper. While in the earlier published paper, the figures described the Ru-complex attached to TiO_2, the same figures have now been used in this article to describe the electron transfer between the Ru-complex and the SnO_2 semiconductor.

References

[1] R. Ghanem, "Light-Induced Tyrosine Radical Formation from Ruthenium-Tyrosine Complex Anchored to SnO_2 Semiconductor," *International Journal of Photoenergy*, vol. 2008, Article ID 524142, 7 pages, 2008.

[2] Y. Xu, J. Pan, T. Hoffmann et al., "Light-Driven Tyrosine Radical Formation in a Ruthenium–Tyrosine Complex Attached to Nanoparticle TiO_2," *Inorganic Chemistry*, vol. 41, no. 24, pp. 6258–6266, 2002.